

Substitute for form 1449A/B/PTO				<i>Complete if Known</i>	
				Application Number	10/812,294-Conf. #1809
				Filing Date	March 29, 2004
				First Named Inventor	Sutherland C. Ellwood, Jr.
				Art Unit	2883
				Examiner Name	T. L. Rude
Sheet	1	of	1	Attorney Docket Number	
20028-7002					

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (#known)			

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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NON PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			²
TR	CA	D. Budker et al., Resonant Magneto-Optic Rotation: New Twists in an Old Plot [online], [referenced in application and retrieved on 2006-03-29 by Examiner Omar Rojas in US Application 10/906,257]. Retrieved from the Internet: http://ist-socrates.berkeley.edu/~budker/papers/ResonantFaradayPaper/resFar.pdf			<input checked="" type="checkbox"/>

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ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

Title of Invention	Faraday structured waveguide							
Application Number :		10/812294						
Confirmation Number:		1809						
First Named Applicant:		Sutherland Ellwood						
Attorney Docket Number:		20028-7002						
Art Unit:		2883						
Examiner:		T. L. Rude						
Search string:		(5844710 or 5889609 or 5901258 or 6103010 or 6208795 or 6333806 or 6339492 or 6417892 or 6441944 or 6542647 or 6577430 or 6757101 or 6762872 or 6813076 or 20010010593 or 20010023932 or 20010032940 or 20020003651 or 20020044710 or 20020139974 or 20020051279 or 20020063941 or 20030031443).pn)						
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Note: Applicant is not required to submit a paper copy of cited US Patent Documents								
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/Timothy Rude/	06/23/2006